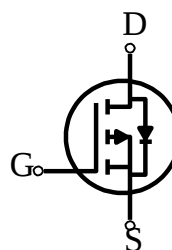


P-Channel High Density Trench MOSFET

FEATURES

- Super high dense cell trench design for low $R_{DS(on)}$.
- Rugged and reliable.
- Surface Mount package.

SOT-23



PRODUCT SUMMARY

VDSS	ID	$R_{DS(on)}$ (m-ohm) Max
-60V	-2A	180@ VGS=10V
	-1.5A	270@VGS= 4.5V

ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	-60	V
Gate-Source Voltage	VGS	± 20	V
Drain Current-Continuous ^a @ $T_A = 25\text{ }^{\circ}\text{C}$ -Pulse ^b	ID	-2	A
	IDM	-8	A
Drain-Source Diode Forward Current ^a	IS	-2	A
Maximum Power Dissipation ^a	PD	1.25	W
		0.75	
Operating Junction and Storage Temperature Range	TJ, Tsig	- 55 to 150	$^{\circ}\text{C}$

THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient ^a	R_{thJA}	100	$^{\circ}\text{C/W}$
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Note

a. Surface Mounted on FR4 Board, $t \leq 10\text{sec}$.

b. Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS (T_A = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ ^c	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V , I _D = -250uA	-60			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -40V , V _{GS} = 0V			-1	uA
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V			-100	nA
ON CHARACTERISTICS ^b						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250uA	-1	-1.6	-3	V
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = -10V ,I _D = -2A		140	180	m-ohm
		V _{GS} = -4.5V , I _D = -1.5A		210	270	m-ohm
DRAIN-SOURCE DIODE CHARACTERISTICS ^b						
Diode Forward Voltage	V _{SD}	V _{GS} = 0V , I _S = -2A			-1.2	V
DYNAMIC CHARACTERISTICS ^c						
Input Capacitance	C _{ISS}	V _{DS} = -60V, V _{GS} = 0V f = 1.0MHz		785		pF
Output Capacitance	C _{OSS}			285		pF
Reverse Transfer Capacitance	C _{RSS}			112		pF
SWITCHING CHARACTERISTICS ^c						
Turn-On Delay Time	t _{D(ON)}	V _{DD} = -60V, I _D = -1A V _{GEN} = -4.5V R _L = 6 ohm R _{GEN} = 6 ohm		10.5		ns
Rise Time	t _r			15.6		ns
Turn-Off Delay Time	t _{D(OFF)}			18.7		ns
Fall Time	t _f			8.2		ns
Total Gate Charge	Q _g	V _{DS} = -6V I _D = -1.5A V _{GS} = -4.5V		8.2		nC
Gate-Source Charge	Q _{gs}			5.8		nC
Gate-Drain Charge	Q _{gd}			3.7		nC

Note

b. Pulse Test Pulse width ≤ 300us , Duty Cycle ≤ 2% .

c. Guaranteed by design , not subject to production testing .

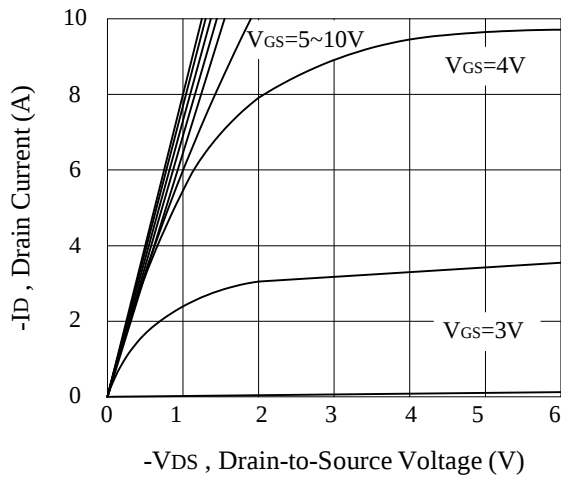


Figure 1. Output Characteristics

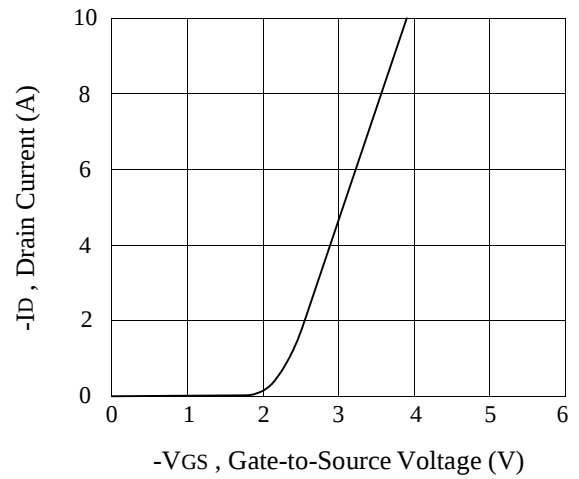


Figure 2. Transfer Characteristics

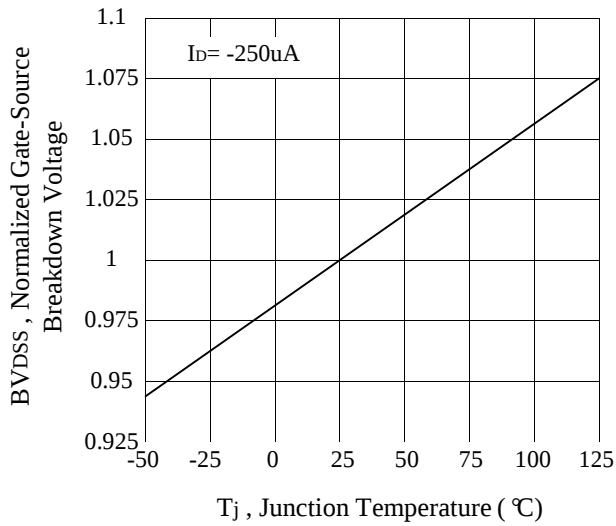


Figure 3. Breakdown Voltage Variation with Temperature

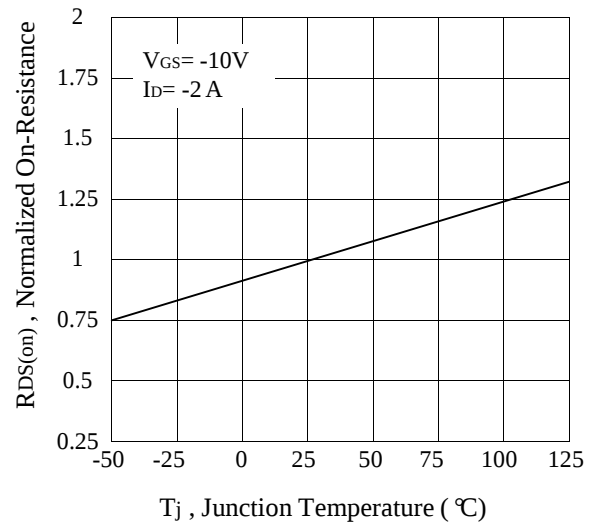


Figure 4. On-Resistance Variation with Temperature

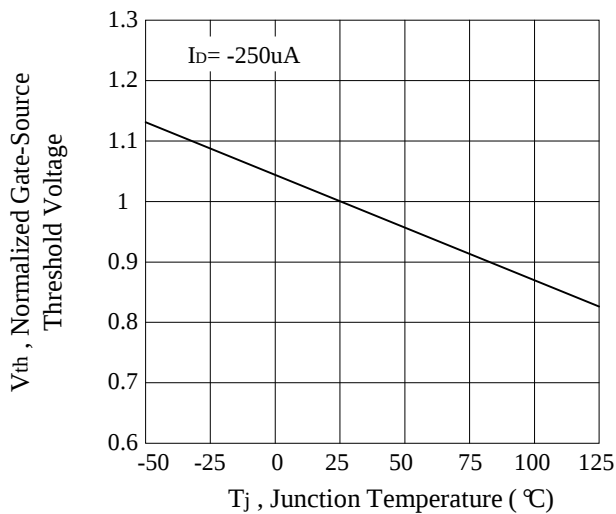


Figure 5. Gate Threshold Variation with Temperature

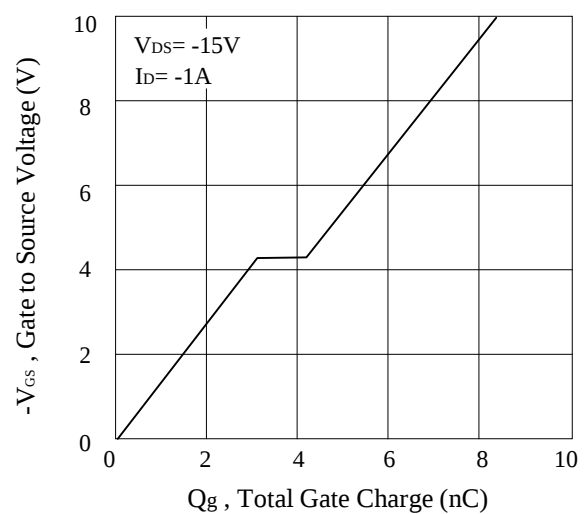
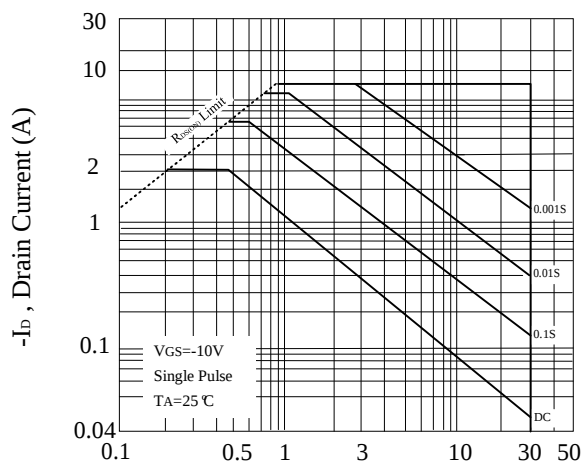
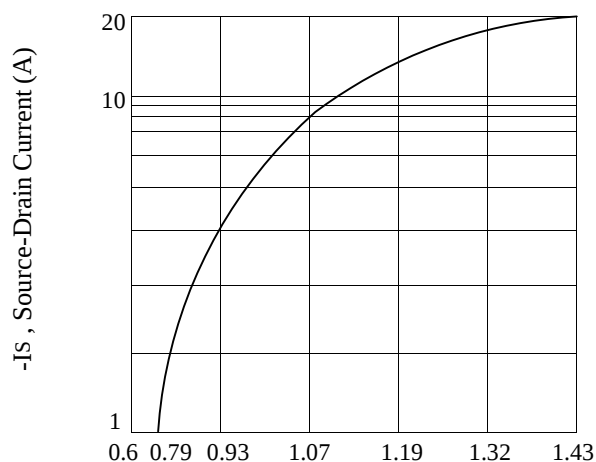


Figure 6. Gate Charge



-VDS, Drain-Source Voltage (V)
 Figure 7. Maximum Safe Operating Area



-VSD, Body Diode Forward Voltage (V)
 Figure 1. Body Diode Forward Voltage Variation with Source Current

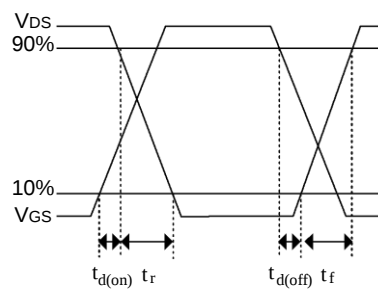
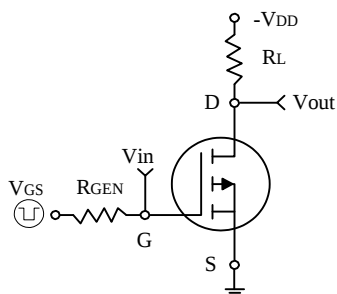


Figure 9. Switching Test Circuit and Switching Waveforms

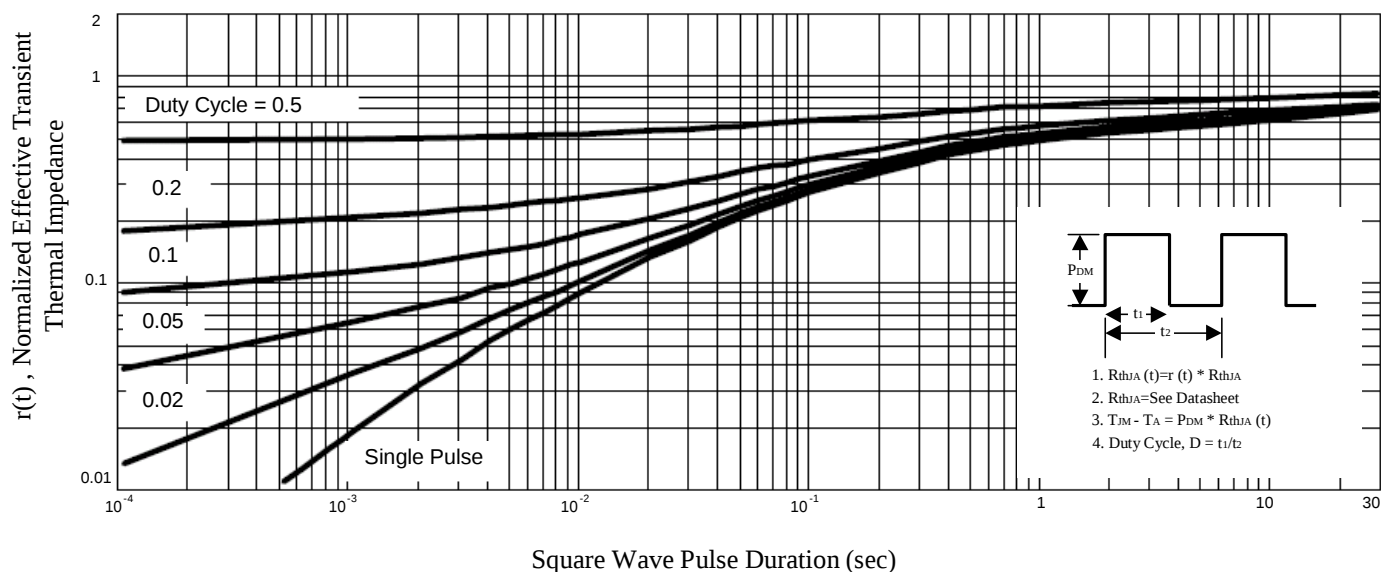


Figure 10. Normalized Thermal Transient Impedance Curve